

What kind of measurement is appropriate ?

Applications	Total thickness d[nm] of layer stack under investigation	Kind of measurement	Number of fitparameters
self-assembled monolayer (SAM), micro-contact-printing (μ CP), Brewster angle microscopy (BAM), Langmuir-Bludgett film, kinetics in liquid cells	$d < 200$	Single pair of Δ and Ψ	1...2
Quality Control of microarray, film on glass substrate, surface plasmon resonance (SPR), thin ($20\text{nm} < d < 1000\text{nm}$) anisotropic films, thick ($2\mu\text{m} < d < 200\mu\text{m}$) isotropic films	$d < 20$ or $d > 2000$	AOI-spectrum	2...3
ITO-film, tiny samples (e.g. cantilever, Laser Diode (LD)), metal substrate with nano-roughness, d/n/k-measurement of a film	$20 < d < 2000$	λ -spectrum	3...8
Organic Light Emitting Device (OLED)	$20 < d < 2000$	Variable Angle spectroscopic Ellipsometry (VASE)	4...8